

SN74CBTK16245

16-BIT FET BUS SWITCH

WITH ACTIVE-CLAMP UNDERSHOOT-PROTECTION CIRCUIT

SCDS105D – APRIL 2000 – REVISED NOVEMBER 2001

- Member of the Texas Instruments Widebus™ Family
- Standard '16245-Type Pinout
- 5-Ω Switch Connection Between Two Ports
- TTL-Compatible Input Levels
- I_{off} Supports Partial-Power-Down Mode Operation
- Active-Clamp Undershoot-Protection Circuit on the I/Os Clamps Undershoots up to -2 V
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)

description

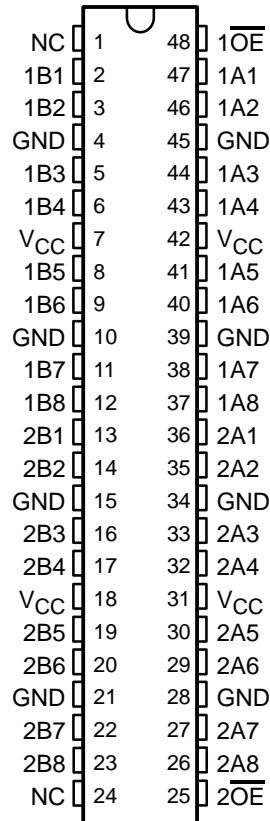
The SN74CBTK16245 device provides 16 bits of high-speed TTL-compatible bus switching in a standard '16245 device pinout. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

The A and B ports have an active-clamp undershoot-protection circuit. When there is an undershoot, the active-clamp circuit is enabled, and current from V_{CC} is supplied to clamp the output, preventing the pass transistor from turning on.

The device is organized as two 8-bit low-impedance switches with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the switch is on, and data can flow from the A port to the B port, or vice versa. When \overline{OE} is high, the switch is open, and the high-impedance state exists between the two ports.

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

DGG, DGV, OR DL PACKAGE
(TOP VIEW)



NC – No internal connection

ORDERING INFORMATION

TA	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	SSOP – DL	Tube	SN74CBTK16245DL	CBTK16245
		Tape and reel	SN74CBTK16245DLR	
	TSSOP – DGG	Tape and reel	SN74CBTK16245DGGR	CBTK16245
	TVSOP – DGV	Tape and reel	SN74CBTK16245DGVR	CP245

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



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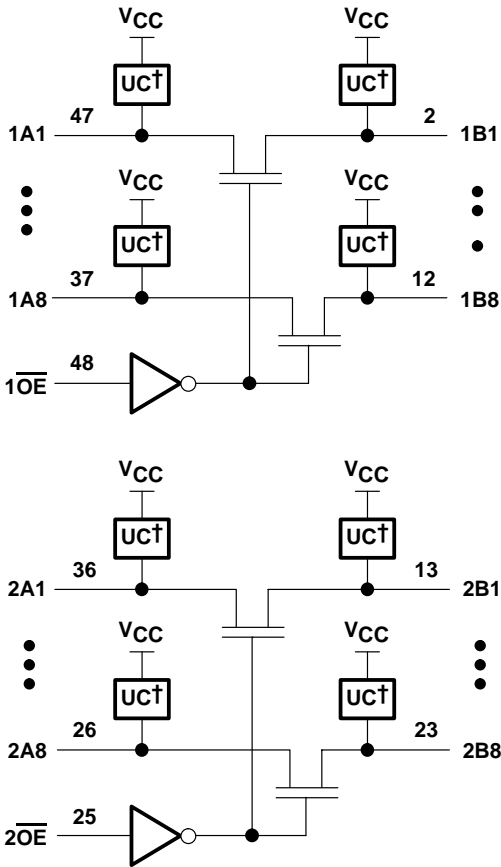
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FUNCTION TABLE
(each 8-bit bus switch)

INPUT OE	FUNCTION
L	A port = B port
H	Disconnect

logic diagram (positive logic)



† Undershoot clamp

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4 V		V _{CC} = 5 V ± 0.5 V		UNIT
			MIN	MAX	MIN	MAX	
t _{pd} [†]	A or B	B or A	0.35		0.25		ns
t _{en}	$\overline{\text{OE}}$	A or B	7.4		1.6	4.9	ns
t _{dis}	$\overline{\text{OE}}$	A or B	7.4		4.2	7.5	ns

[†] The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

undershoot characteristics

PARAMETER	TEST CONDITIONS	MIN	TYP [‡]	MAX	UNIT
V _{OUTU}	See Figures 1 and 2, and Table 1	2	V _{OH} -0.3		V

[‡] All typical values are at V_{CC} = 5 V (unless otherwise noted), T_A = 25°C.

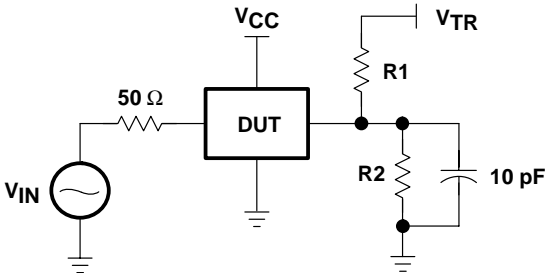


Figure 1. Device Test Setup

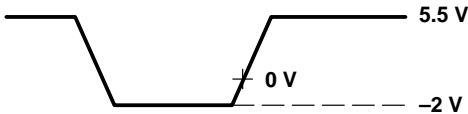


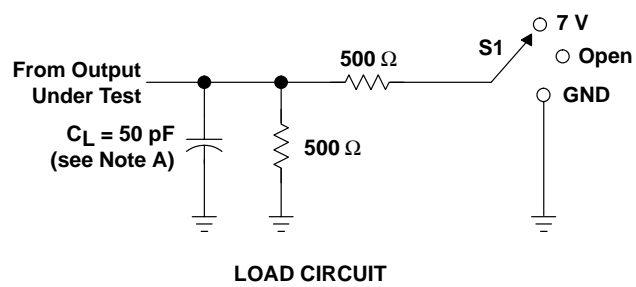
Figure 2. Transient Input Voltage Waveform

Table 1. Device Test Conditions

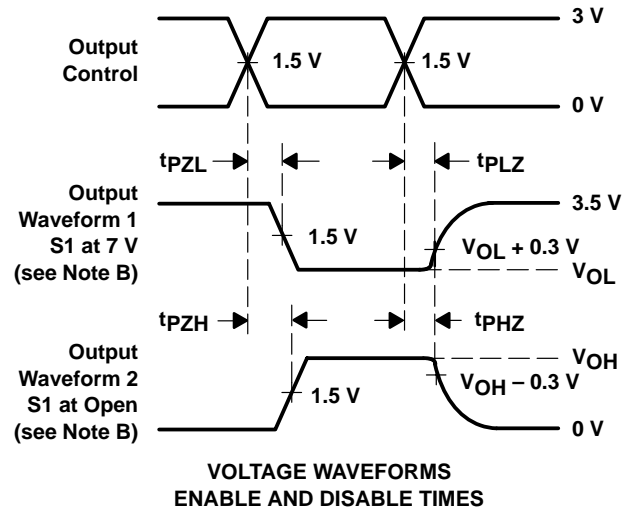
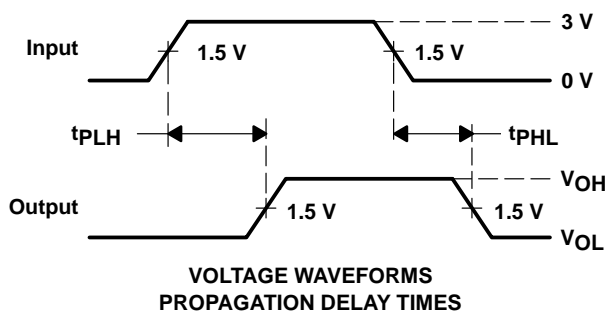
PARAMETER	VALUE	UNIT
B port under test [§]	See Figure 1	
V _{IN}	See Figure 2	V
t _w	20	ns
t _r	2	ns
t _f	2	ns
R1 = R2	100	kΩ
V _{TR}	11	V
V _{CC}	5.5	V

[§] Other B-port outputs are open.

PARAMETER MEASUREMENT INFORMATION



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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